Generalization Performance

Statistical Inference with Reproducing Kernel Hilbert Space

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- Risk and empirical risk
- Concentration inequalities
- Bound for finite function class

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- Techniques for infinite function class
- Rademacher average, growth function, and VC-dimension

3 Risk bound for SVM

Risk bound for SVM

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Bounding risk

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2 Risk bound for infinite function class

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Risk and empirical risk I: Terminology

- Supervised learning:
 - $\mathcal{D} = \{(X_1, Y_1), \dots, (X_n, Y_n)\}$: data. i.i.d. sample.
 - $X_i \in \mathcal{X}$: input, $Y_i \in \mathcal{Y}$: output.
 - $\mathcal{F} \subset \{f : \mathcal{X} \to \mathcal{Y}\}$: function class.
 - Choose f from \mathcal{F} so that $Y_i \approx f(X_i)$.
- Risk and empirical risk
 - Loss function $\ell(y, f)$: measure discrepancy of Y_i and $f(X_i)$.
 - Risk: the purpose of learning is to minimize the risk;

$$L(f) = E[\ell(Y, f(X))] \qquad (f \in \mathcal{F}).$$

Empirical risk:

$$L_n(f) = \widehat{E}_n[\ell(Y, f(X))] = \frac{1}{n} \sum_{i=1}^n \ell(Y_i, f(X_i)) \qquad (f \in \mathcal{F}).$$

• Learning must be done with data:

$$\widehat{f} = \arg\min_{f\in\mathcal{F}} L_n(f).$$

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Risk and empirical risk II: Example of loss function

- Mean square error.
 - $\ell(y, f) = (y f)^2$.
 - Empirical risk

 $\min_{f \in \mathcal{F}} \sum_{i=1}^{n} (Y_i - f(X_i))^2$ (least mean square).

- Risk = $E[(Y f(X))^2]$.
- 0-1 loss. $y, f(x) \in \{\pm 1\}.$
 - $\ell(y, f) = \frac{1 yf(x)}{2}$.
 - Empirical risk = ratio of errors: $\widehat{E}_n[\ell(Y, f(X))] = \frac{1}{n} |\{i \mid Y_i \neq f(X_i)\}|.$
 - Risk = mean error rate: $E[\ell(Y, f(X))] = Pr(Y \neq f(X))$.
- Log likelihood
 - $\ell(y, f) = -\log p(y|f).$
 - Empirical risk = Empirical log likelihood.
 - Risk = Expected log likelihood.

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Risk and empirical risk III: Two approaches

• Goal: What can we say about $L(\widehat{f})$?

$$L(\widehat{f}) - \underbrace{\widehat{L}_n(\widehat{f})}_{\text{known}} = \underbrace{E[\ell(Y,\widehat{f}(X))|\mathcal{D}] - \widehat{E}_n[\ell(Y,\widehat{f}(X))]}_?$$

- Approaches to analysis.
 - Asymptotic expansion of the expectation:

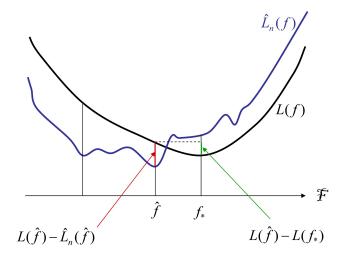
e.g.
$$E_{\mathcal{D}}[E[\ell(Y, \hat{f}(X))] - \hat{E}_n[\ell(Y, \hat{f}(X))]] = \frac{A}{n} + ...$$

 $\Longrightarrow \mathsf{AIC}.$

Bounding risk:

$$\begin{split} \text{e.g.} \quad & \Pr \big(E[\ell(Y, \widehat{f}(X)) | \mathcal{D}] \leq \widehat{E}_n[\ell(Y, \widehat{f}(X))] + \varepsilon \big) \\ & \leq \Pr \Big(\sup_{f \in \mathcal{F}} \big(E[\ell(Y, f(X))] - \widehat{E}_n[\ell(Y, f(X))] \big) \leq \varepsilon \Big) \quad \leq \alpha e^{-\beta \varepsilon^2 n}. \end{split}$$

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Risk and empirical risk IV

- This lecture explains the latter approach
 - The bound applies for all *n*, not asymptotics.
 - Just a bound, but often derives a useful information in its functional form.
 - Can be applied to complex methods, such as SVM, AdaBoost.
 - Note: the loss function of SVM $(1 yf(x))_+$ is not differentiable.
- The techniques explained here use the notion of Rademacher average [BBM02].
 For more classical background, see [Vap98].
- Comment on terminology:¹
 - Risk = generalization error, prediction error, (expected log likelihood), etc.
 - Empirical risk = empirical error, training error, (empirical log likelihood), etc.

1The terminology in statistical learning theory is slightly different from statistics.

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Empirical mean and expectation

Before considering

$$\sup_{f\in\mathcal{F}} E[\ell(Y, f(X))] - \widehat{E}_n[\ell(Y, f(X))],$$

review the behavior of

$$E[\ell(Y, f(X))] - \widehat{E}_n[\ell(Y, f(X))] = E[Z] - \frac{1}{n} \sum_{i=1}^n Z_i.$$

• The law of large numbers (Z_i: i.i.d.)

$$\frac{1}{n}\sum_{i=1}^{n}Z_{i} \longrightarrow E[Z] \quad a.e.(n \to \infty)$$

• Central limit theorem (Z_i: i.i.d.)

$$\sqrt{n} \left(\frac{1}{n} \sum_{i=1}^{n} Z_i\right) - E[Z] \Longrightarrow N(0, \operatorname{Var}[Z]) \quad (n \to \infty)$$

How about

$$\Pr\left(\frac{1}{n}\sum_{i=1}^{n}Z_{i}-E[Z]\geq\varepsilon\right)?$$

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Hoeffding's inequality

Theorem (Hoeffding's inequality)

 X_1, \ldots, X_n : independent random variables, $X_i \in [a_i, b_i]$. Then, for any $\varepsilon > 0$,

$$\Pr\left(\frac{1}{n}\sum_{i=1}^{n}X_{i}-E[X]>\varepsilon\right)\leq \exp\left(\frac{-2\varepsilon^{2}n^{2}}{\sum_{i=1}^{n}(b_{i}-a_{i})^{2}}\right)$$

and

$$\Pr\left(\frac{1}{n}\sum_{i=1}^{n}X_{i}-E[X]<-\varepsilon\right)\leq\exp\left(\frac{-2\varepsilon^{2}n^{2}}{\sum_{i=1}^{n}(b_{i}-a_{i})^{2}}\right)$$

- Proof is omitted (see e.g. [vdVW96]), since this is a corollary to McDiamid's inequality).
- Example:

If $\ell(y, f) \in [0, 1]$, then for any $f \in \mathcal{F}$,

$$\Pr(|\hat{L}_n(f) - L(f)| > \varepsilon) \le 2e^{-2\varepsilon^2 n}.$$

Azuma-Hoeffding's/McDiamid's inequality

Theorem (Azuma-Hoeffding's/McDiamid's inequality)

 X_1, \ldots, X_n : independent random variables on \mathcal{X} . $f : \mathcal{X}^n \to \mathbb{R}$: measurable function. Assume for each *i* there exists $c_i > 0$ such that for any x_1, \ldots, x_n, x'_i

$$|f(x_1,\ldots,x_i,\ldots,x_n) - f(x_1,\ldots,x'_i,\ldots,x_n)| \le c_i$$

then

$$\Pr(f(X_1,\ldots,X_n) - E[f(X_1,\ldots,X_n)] > \varepsilon) \le \exp\left(\frac{-2\varepsilon^2}{\sum_{i=1}^n c_i^2}\right)$$

and

$$\Pr(f(X_1,\ldots,X_n) - E[f(X_1,\ldots,X_n)] < -\varepsilon) \le \exp\left(\frac{-2\varepsilon^2}{\sum_{i=1}^n c_i^2}\right)$$

Risk and empirical risk Concentration inequalities Bound for finite function class

Proof I

Remark. $f(x_1, ..., x_n) = \sum_{i=1}^n X_i$ and $c_i = b_i - a_i$ prove Hoeffding's inequality. proof. Let

$$V_{i} = E[f(X_{1}, \dots, X_{n}) | X_{1}, \dots, X_{i}] - E[f(X_{1}, \dots, X_{n}) | X_{1}, \dots, X_{i-1}]$$

= $E[f(X_{1}, \dots, X_{n}) | X_{1}, \dots, X_{i}]$
 $- E_{X_{i}}[E[f(X_{1}, \dots, X_{n}) | X_{1}, \dots, X_{i}] | X_{1}, \dots, X_{i-1}]$

Then,

$$\sum_{i=1}^{n} V_i = f - E[f], \text{ and } E[V_i \mid X_1, \dots, X_{i-1}] = 0.$$

By Markov's inequality with e^{tx} (t > 0),

$$\Pr(f - E[f] > \varepsilon) = \Pr(\sum_{i=1}^{n} V_i > \varepsilon)$$

$$\leq \inf_{t>0} e^{-t\varepsilon} E\left[e^{t\sum_{i=1}^{n} V_i}\right]$$

$$= \inf_{t>0} e^{-t\varepsilon} E\left[E_{X_n}\left[e^{t\sum_{i=1}^{n} V_i} \mid X_1, \dots, X_{n-1}\right]\right]$$

$$= \inf_{t>0} e^{-t\varepsilon} E\left[e^{t\sum_{i=1}^{n-1} V_i} E_{X_n}\left[e^{tV_n} \mid X_1, \dots, X_{n-1}\right]\right] \qquad [V_1, \dots, V_{n-1} \perp X_n].$$

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Proof II

Let

$$L_i \equiv \inf_x V_i(x_1, \dots, x_{i-1}, x) \le V_i \le \sup_x V_i(x_1, \dots, x_{i-1}, x) \equiv U_i.$$

By the assumption, it is easy to see

$$U_i - L_i \le c_i.$$

From the lemma shown below, $E[e^{tV_n} \mid X_1, \ldots, X_{n-1}] \leq e^{t^2 c_n^2/8}$. Thus,

$$\Pr(f - E[f] > \varepsilon) \le \inf_{t>0} e^{-t\varepsilon} E\left[e^{t\sum_{i=1}^{n-1} V_i}\right] e^{-t^2 c_n^2/8}.$$

Repeating the same argument n-1 times,

$$\Pr(f - E[f] > \varepsilon) \le \inf_{t>0} e^{-t\varepsilon} e^{-t^2 \sum_{i=1}^n c_i^2/8}.$$

The optimal choice $t = 4\varepsilon / \sum_{i=1}^{n} c_i^2$ gives

$$\Pr(f(X_1,\ldots,X_n) - E[f(X_1,\ldots,X_n)] > \varepsilon) \le \exp\left(\frac{-2\varepsilon^2}{\sum_{i=1}^n c_i^2}\right).$$

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Lemmas

Lemma (Hoeffding's lemma)

Let X be a random variable with E[X] = 0 and $a \le X \le b$. Then for any t > 0,

 $E[e^{tX}] \le e^{t^2(b-a)^2/8}.$

Proof omitted (exercise).

Lemma (Markov's inequality)

Let X be a random variable such that $X \ge 0$. Then, for any $\varepsilon > 0$

$$\Pr(X \ge \varepsilon) \le \frac{E[X]}{a}.$$

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Bound for finite function class I

The simplest case: $|\mathcal{F}| < \infty$ (finite class). $\ell(y, f) \in [0, 1]$.

• For each $f \in \mathcal{F}$,

$$\Pr\left(E[\ell(Y, f(X))] - \widehat{E}_n[\ell(Y, f(X))] \ge \varepsilon\right) \le e^{-2\varepsilon^2 n}$$

• From
$$\Pr(A \cup B) \le \Pr(A) + \Pr(B)$$
,

 $\Pr\Bigl(\sup_{f\in\mathcal{F}}\bigl\{E[\ell(Y,f(X))]-\widehat{E}_n[\ell(Y,f(X))]\bigr\}\ge \varepsilon\Bigr)\le |\mathcal{F}|e^{-2\varepsilon^2n}.$

• Let $\delta = |\mathcal{F}|e^{-2\varepsilon^2 n}$. With probability at least $1 - \delta$,

$$\sup_{f \in \mathcal{F}} \left\{ E[\ell(Y, f(X))] - \widehat{E}_n[\ell(Y, f(X))] \right\} \le \sqrt{\frac{\log |\mathcal{F}| + \log(1/\delta)}{2n}}$$

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Bound for finite function class II

Two results:

• Estimation of the risk by the empirical risk. With probability at least $1 - \delta$,

$$L(\widehat{f}) \le \widehat{L}_n(\widehat{f}) + \sqrt{\frac{\log |\mathcal{F}| + \log(1/\delta)}{2n}}.$$

• The difference from the optimal risk. $f_* = \arg \min_{f \in \mathcal{F}} L(f)$. With probability at least $1 - 2\delta$,

$$L(\widehat{f}) \le L(f_*) + \sqrt{\frac{\log(1/\delta)}{2n}} + \sqrt{\frac{\log|\mathcal{F}| + \log(1/\delta)}{2n}}$$

Proof.

$$\begin{split} L(\widehat{f}) &= (L(\widehat{f}) - \widehat{L}_n(\widehat{f})) + (\widehat{L}_n(\widehat{f}) - \widehat{L}_n(f_*)) + (\widehat{L}_n(f_*) - L(f_*)) + L(f_*) \\ &\leq (\text{uniform bound}) + (\leq 0) + (\text{Hoeffding}). \end{split}$$

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Extension of risk bound to infinite classes

We wish to extend the uniform bound to an infinite function class \mathcal{F} ;

$$\sup_{f \in \mathcal{F}} \left\{ E[\ell(Y, f(X))] - \widehat{E}_n[\ell(y, f(X))] \right\}.$$

Consider in general $\mathcal{G} \subset \{g: \mathcal{Z} \rightarrow [0,1]\}$ and

$$\sup_{g \in \mathcal{G}} \{ E[g(Z)] - \widehat{E}_n[g(Z)] \}.$$

$$\mathsf{Ex.}\ \mathcal{Z} = \mathcal{X} \times \mathcal{Y} \text{ and } \mathcal{G} = \ell_{\mathcal{F}} = \{\ell(y, f(x)) \mid f \in \mathcal{F}\}.$$

The method consists of three steps:

- Concentration by Azuma-Hoeffding's inequality.
- **2** Symmetrization for removing E[g].
- Bounding Rademacher average.

Step 1: Concentration

Define

$$h(z_1,\ldots,z_n) = \sup_{g \in \mathcal{G}} \left\{ E[g(Z)] - \frac{1}{n} \sum_{i=1}^n g(z_i) \right\}.$$

• h satisfies the condition

$$|h(z_1,\ldots,z_{i-1},z_i,\ldots,z_n) - h(z_1,\ldots,z_{i-1},z'_i,\ldots,z_n)| \le 1/n.$$

• Apply Azuma-Hoeffding's inequality to h: With probability $\geq 1 - \delta$,

$$\sup_{g \in \mathcal{G}} \left\{ E[g(Z)] - \widehat{E}_n[g(Z)] \right\} \le E \left[\sup_{g \in \mathcal{G}} \left\{ E[g(Z)] - \widehat{E}_n[g(Z)] \right\} \right] + \sqrt{\frac{\log(1/\delta)}{2n}}$$

Step 2: Symmetrization - (1)

We wish to have

$$E\left[\sup_{g\in\mathcal{G}}\left\{E[g(Z)]-\widehat{E}_n[g(Z)]\right\}\right]$$

converge to zero.

• Symmetrization. Z'_1, \ldots, Z'_n : an i.i.d. sample with the same distribution as Z_i .

$$\begin{split} &E\left[\sup_{g\in\mathcal{G}}\left\{E[g(Z)]-\widehat{E}_{n}[g(Z)]\right\}\right]=E\left[\sup_{g\in\mathcal{G}}\left\{E\left[\frac{1}{n}\sum_{i=1}^{n}g(Z_{i}')\right]-\frac{1}{n}\sum_{i=1}^{n}g(Z_{i})\right]\right\}\\ &=E\left[\sup_{g\in\mathcal{G}}E\left[\frac{1}{n}\sum_{i=1}^{n}(g(Z_{i}')-g(Z_{i}))\mid Z\right]\right]\\ &\leq E\left[E\left[\sup_{g\in\mathcal{G}}\left\{\frac{1}{n}\sum_{i=1}^{n}(g(Z_{i}')-g(Z_{i}))\right\}\mid Z\right]\right] \qquad \text{[convexity of sup]}\\ &=E\left[\sup_{g\in\mathcal{G}}\left\{\frac{1}{n}\sum_{i=1}^{n}(g(Z_{i}')-g(Z_{i}))\right\}\right]\end{split}$$

• This removes the *infinite sample E*[*g*], and makes a bound with a finite sample.

Step 2: Symmetrization - (2)

- We wish to remove the double sample Z_i and Z'_i .
- Rademacher variables: i.i.d. random variable $\sigma_i \in \{\pm 1\}$ with probability 1/2 for each value.
- Note: By the symmetry,

$$\sum_{i=1}^{n} (g(Z'_i) - g(Z_i))$$
 and $\sum_{i=1}^{n} \sigma_i (g(Z'_i) - g(Z_i))$

have the same law. Hence,

$$\begin{split} &E\left[\sup_{g\in\mathcal{G}}\left\{\frac{1}{n}\sum_{i=1}^{n}(g(Z'_{i})-g(Z_{i}))\right\}\right]\\ &=E\left[\sup_{g\in\mathcal{G}}\left\{\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}(g(Z'_{i})-g(Z_{i}))\right\}\right]\\ &\leq E\left[\sup_{g\in\mathcal{G}}\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}g(Z'_{i})\right]+E\left[\sup_{g\in\mathcal{G}}\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}g(Z_{i})\right]\\ &=2E\left[\sup_{g\in\mathcal{G}}\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}g(Z_{i})\right]. \end{split}$$

Step 3: Rademacher average

$$E\left[\sup_{g\in\mathcal{G}}\left\{E[g(Z)] - \widehat{E}_n[g(Z)]\right\}\right] \le 2E\left[\sup_{g\in\mathcal{G}}\frac{1}{n}\sum_{i=1}^n \sigma_i g(Z_i)\right].$$

• Rademacher average:

$$R_n(\mathcal{G}) \equiv E\left[\sup_{g \in \mathcal{G}} \frac{1}{n} \sum_{i=1}^n \sigma_i g(Z_i)\right].$$

• Empirical Rademacher average:

$$\widehat{R}_n(\mathcal{G}) \equiv E \left[\sup_{g \in \mathcal{G}} \frac{1}{n} \sum_{i=1}^n \sigma_i g(Z_i) \mid Z_1, \dots, Z_n \right].$$

- Note: $E[\sigma_i g(Z_i)] = 0$. Thus, $\frac{1}{n} \sum_i \sigma_i g(Z_i)$ must be small.
- $R_n(\mathcal{G})$ $(\widehat{R}_n(\mathcal{G}))$ represents the complexity of the function class \mathcal{G} . Example: $\mathcal{G} \subset \{g : \{Z_1, \dots, Z_n\} \to \{\pm 1\}\}$. Regard σ_i as a label of Z_i . $\frac{1}{n} \sum_{i=1}^n \sigma_i g(Z_i) = \frac{1}{n} \sum_{i=1}^n (1 - 2I_{\{\sigma_i \neq g(Z_i)\}}) = 1 - 2\widehat{L}_n(g)$. $R_n(\mathcal{G}) = 1 - 2 \times$ (expected minimum empirical loss).

Risk bound for infinite classes

We have obtained: With probability $\geq 1 - \delta$,

$$\sup_{g \in \mathcal{G}} \left\{ E[g(Z)] - \widehat{E}_n[g(Z)] \right\} \le 2R_n(\mathcal{G}) + \sqrt{\frac{\log(1/\delta)}{2n}}$$

Two consequences:

 $\ell(y, f) \in [0, 1]$, and let $\ell_{\mathcal{F}} = \{\ell(y, f(x)) \mid f \in \mathcal{F}\}.$

• Estimation of the risk by the empirical risk. With probability at least $1 - \delta$,

$$L(\widehat{f}) \leq \widehat{L}_n(\widehat{f}) + 2R_n(\ell_{\mathcal{F}}) + \sqrt{\frac{\log(1/\delta)}{2n}}.$$

The difference from the best possible risk.
 f_{*} = arg min_{f∈F} L(f). With probability at least 1 − 2δ,

$$L(\widehat{f}) \le L(f_*) + 2R_n(\ell_{\mathcal{F}}) + 2\sqrt{\frac{\log(1/\delta)}{2n}}$$

Relations between $R_n(\ell_F)$ and $R_n(F)$

The bound includes $R_n(\ell_{\mathcal{F}})$.

It is often related to $R_n(\mathcal{F})$, which is easier to analyze.

- 0-1 loss: $\mathcal{F} \subset \{f : \mathcal{X} \to \{\pm 1\}\}, \, \ell(y, f) = \frac{1-yf}{2}.$
- Fact: for 0-1 loss,

$$R_n(\ell_{\mathcal{F}}) = \frac{1}{2}R_n(\mathcal{F}).$$

Proof.

$$\begin{split} R_n(\ell_{\mathcal{F}}) &= E \Big[\sup_{f \in \mathcal{F}} \sum_{i=1}^n \sigma_i \frac{1 - Y_i f(X_i)}{2} \Big] \\ &= \frac{1}{2} E \Big[\sup_{f \in \mathcal{F}} \sum_{i=1}^n (-\sigma_i Y_i) f(X_i) \Big] \\ &= \frac{1}{2} R_n(\mathcal{F}) \qquad [(-\sigma_i Y_i) \text{ works as a Rademacher variable}] \end{split}$$

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Bounding Rademacher average I

How to bound the Rademacher average ?

$$R_n(\mathcal{G}) = E\left[\sup_{g \in \mathcal{G}} \sum_{i=1}^n \sigma_i g(Z_i)\right]$$

Assume $\mathcal{G} \subset \{g : \mathcal{Z} \to \{\pm 1\}\}.$

Note: \mathcal{G} affects on $R_n(\mathcal{G})$ only through $(g(Z_1), \ldots, g(Z_n)) \in \{\pm 1\}^n$.

We can use the following lemma.

Lemma (Massart [Mas])

A: finite subset of \mathbb{R}^n . Assume $\max_{a \in A} ||a|| \le R$. Then

$$E\left[\max_{a\in A}\sum_{i=1}\sigma_i a_i\right] \le R\sqrt{2\log|A|},$$

where σ_i are Rademacher variables.

Bounding Rademacher average II

For
$$Z_1^n = (Z_1, \dots, Z_n) \in \mathcal{Z}^n$$
, define
 $\mathcal{G}_{|Z_1^n} = \left\{ \left(g(Z_1), \dots, g(Z_n) \right) \in \{\pm 1\}^n \mid g \in \mathcal{G} \right\}.$

Fact:

$$R_n(\mathcal{G}) \le \sqrt{\frac{2E[\log |\mathcal{G}_{|Z_1^n}|]}{n}} \le \sqrt{\frac{2\log E[|\mathcal{G}_{|Z_1^n}|]}{n}}.$$

Proof.

$$\begin{aligned} R_n(\mathcal{G}) &= E\left[\sup_{a \in \mathcal{G}_{|Z_1^n}} \frac{1}{n} \sum_{i=1}^n \sigma_i a_i\right] \\ &= E\left[E\left[\sup_{a \in \mathcal{G}_{|Z_1^n}} \frac{1}{n} \sum_{i=1}^n \sigma_i a_i \mid Z_1^n\right]\right] \\ &\leq \frac{1}{\sqrt{n}} E\left[\sqrt{2 \log |\mathcal{G}_{|Z_1^n}|}\right] \qquad \text{[Massart's lemma]} \\ &\leq \sqrt{\frac{2E[\log |\mathcal{G}_{|Z_1^n}|]}{n}} \qquad \text{[concavity of } \sqrt{-}] \\ &\leq \sqrt{\frac{2 \log E[|\mathcal{G}_{|Z_1^n}|]}{n}} \qquad \text{[concavity of } \log] \end{aligned}$$

Proof of Massart's lemma

Proof.

Let s > 0.

$$\begin{split} \exp(sE[\max_a\sum_i\sigma_ia_i]) &\leq E[\exp(s\max_a\sum_i\sigma_ia_i)] \qquad [\text{convexity of } \exp(sz)] \\ &= E[\max_a\exp(s\sum_i\sigma_ia_i)] \qquad [\max \longrightarrow \sum] \\ &\leq E[\sum_a\exp(s\sum_i\sigma_ia_i)] \qquad [\max \longrightarrow \sum] \\ &= \sum_a E[\prod_{i=1}^n e^{s\sigma_ia_i}] \qquad [\text{independence of } \sigma_i] \\ &= \sum_{a \in A} \prod_{i=1}^n E[e^{s\sigma_ia_i}] \\ &\leq \sum_{a \in A} \prod_{i=1}^n \exp(s^24a_i^2/8) \\ \qquad \qquad [\text{Hoeffding's lemma, } \sigma_ia_i \in [-a_i,a_i]] \\ &= |A|\exp(s^2R^2/2). \end{split}$$
Take the optimal $s = \sqrt{\frac{2\log|A|}{R^2}}$. Then,
 $E[\max_a\sum_i\sigma_ia_i] \leq R\sqrt{2\log|A|}.$

Distribution-free bound: Growth function

Let $\mathcal{G} \subset \{g : \mathcal{Z} \to \{\pm 1\}\}$. Definition. Growth function

 $\Pi_{\mathcal{G}}(n) = \max\{|\mathcal{G}_{|Z_1^n}| \in \mathbb{N} \mid Z_1^n = (Z_1, \dots, Z_n) \in \mathcal{Z}^n\}.$

 $\Pi_{\mathcal{G}}(n)$ is monotonically decreasing w.r.t. n.

Definition. Vapnik-Chervonenkis (VC) dimension

$$\dim_{VC}(\mathcal{G}) = \max\{n \in \mathbb{N} \mid \Pi_{\mathcal{G}}(n) = 2^n\}$$

Example: linear threshold functions on \mathbb{R}^d .

$$\mathcal{G} = \{ sgn(w^T x + b) \mid w \in \mathbb{R}^d, b \in \mathbb{R} \},\$$

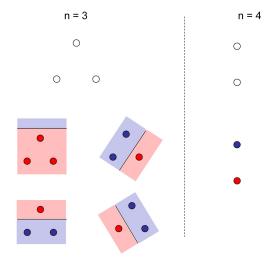
$$\dim_{VC}(\mathcal{G}) = d + 1.$$

Risk bound for infinite function class Risk bound for SVM

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d = 2



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Techniques for infinite function class Rademacher average, growth function, and VC-dimension

Sauer's lemma

Theorem (Sauer's lemma)

$$\mathcal{G} \subset \{g: \mathcal{Z} \rightarrow \{\pm 1\}\}$$
. dim $_{VC}(\mathcal{G}) = d$. Then,

$$\Pi_{\mathcal{G}}(n) \le \sum_{i=0}^{d} \binom{n}{i}$$

and for $n \ge d$,

$$\Pi_{\mathcal{G}}(n) \le \left(\frac{en}{d}\right)^d.$$

Corollary (Distribution-free bound of Rademacher average)

 $\mathcal{G} \subset \{g : \mathcal{Z} \rightarrow \{\pm 1\}\}.$ dim $_{VC}(\mathcal{G}) = d.$ Then,

$$R_n(\mathcal{G}) \le \sqrt{\frac{2\log \Pi_{\mathcal{G}}(n)}{n}} \le \sqrt{\frac{2d(\log n + \log(e/d))}{n}}.$$

For the proof of Sauer's lemma, see [Vap98].

Bound of risk I

$$\mathcal{F} \subset \{f : \mathcal{X} \to \{\pm 1\}\}. \ \dim_{VC}(\mathcal{F}) = d.$$

Recall $R_n(\ell_{\mathcal{F}}) = \frac{1}{2}R_n(\mathcal{F}) \leq \frac{1}{2}\sqrt{\frac{2d\log n + 2d\log(e/d))}{n}} \text{ for } n \geq d.$

Distribution-free bound of risk.

• Estimation of the risk by the empirical risk. With probability at least $1 - \delta$,

$$L(\widehat{f}) \le \widehat{L}_n(\widehat{f}) + \sqrt{\frac{2d\log n + 2d\log(e/d))}{n}} + \sqrt{\frac{\log(1/\delta)}{2n}}.$$

• The difference from the best possible risk. $f_* = \arg \min_{f \in \mathcal{F}} L(f)$. With probability at least $1 - 2\delta$,

$$L(\widehat{f}) \le L(f_*) + \sqrt{\frac{2d\log n + 2d\log(e/d))}{n}} + 2\sqrt{\frac{\log(1/\delta)}{2n}}.$$

Bound of risk II

• Risk bound: With Probability $\geq 1 - \delta$,

$$L(\widehat{f}) \leq \widehat{L}_n(\widehat{f}) + \sqrt{\frac{2d\log n}{n} + \frac{2d\log(e/d))}{n}} + \sqrt{\frac{\log(1/\delta)}{2n}}$$

AIC:

$$E_{\mathcal{D}}[L(\widehat{f})] \approx E_{\mathcal{D}}[L(\widehat{f})] + \frac{\text{\# parameters}}{n}$$

MDL:

$$\mathsf{MDL} = E_{\mathcal{D}}[L(\widehat{f})] + \frac{\# \operatorname{parameters} \log n}{n}.$$

Techniques for infinite function class Rademacher average, growth function, and VC-dimension

Properties of Rademacher average I

1	
	$\mathcal{F} \subset \mathcal{G} \implies R_n(\mathcal{F}) \subset R_n(\mathcal{G}).$
2	$R_n(c\mathcal{F}) = c R_n(\mathcal{F}),$
	where $c \in \mathbb{R}$ and $c\mathcal{F} = \{cf \mid f \in \mathcal{F}\}.$
3	For $F + g = \{f + g \mid f \in \mathcal{F}\},\$
	$R_n(\mathcal{F}+g) = R_n(\mathcal{F}).$
4	Assume $-\mathcal{F}=\mathcal{F}$. Then,
	$R_n(\mathbf{co}\mathcal{F}) = R_n(\mathcal{F}),$

where $\operatorname{co}\mathcal{F} = \{\sum_{i=1}^{m} a_i f_i \mid f_i \in \mathcal{F}, a_i \ge 0, \sum_{i=1}^{n} a_i = 1\}.$

Properties of Rademacher average II

So Let $\phi_i : \mathbb{R} \to \mathbb{R}$ (i = 1, ..., n) be Lipschitz continuous with Lipschitz constant *b*, i.e.,

$$|\phi_i(x) - \phi_i(y)| \le b|x - y| \qquad (\forall x, y).$$

Then,

$$E\left[\sup_{f\in\mathcal{F}}\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}\phi_{i}(f(X_{i}))\right] \leq bE\left[\sup_{f\in\mathcal{F}}\frac{1}{n}\sum_{i=1}^{n}\sigma_{i}f(X_{i})\right] = bR_{n}(\mathcal{F}),$$

where σ_i are Rademacher constants.

Proof is omitted. For (5), see [LT91], Th.4.12.

Rademacher average vs distribution-free bound

How to measure the complexity of function classes.

- VC-dimension is simple and easy to compute or bound for many function classes.
- VC-dimension does not take the distribution of X into account.
- Rademacher average includes the distribution of *X*.
- It may not be easy to compute.
- Various useful properties. (For Rademacher averages, see [BM02], [LT91].)

Mini-summary on risk bound

• With probability $\geq 1 - \delta$,

(Risk) \leq (Empirical risk) + (Complexity of \mathcal{F}) + $\Theta(1/\delta)$.

- The bound applies to all *n*, but usually meaningful for large *n*.
- The functional form of the complexity term reflects the property of the function class and learning method.
- Rademacher average represents the complexity term. It is upper bounded by using VC dimension.

Bounding risk

- Risk and empirical risk
- Concentration inequalities
- Bound for finite function class

2 Risk bound for infinite function class

- Techniques for infinite function class
- Rademacher average, growth function, and VC-dimension
- Risk bound for SVM
 Risk bound for SVM

Review of risk bound I

- Assume loss function $\ell(y, f) \in [0, 1]$, and let $\ell_{\mathcal{F}} = \{\ell(y, f(x)) \mid f \in \mathcal{F}\}.$
- Risk: the purpose of learning is to minimize the risk;

$$L(f) = E[\ell(Y, f(X))] \qquad (f \in \mathcal{F}).$$

Empirical risk:

$$\widehat{L}_n(f) = \widehat{E}_n[\ell(Y, f(X))] = \frac{1}{n} \sum_{i=1}^n \ell(Y_i, f(X_i)) \qquad (f \in \mathcal{F}).$$

• Learning:

$$\widehat{f} = \arg\min_{f\in\mathcal{F}} L_n(f).$$

Review of risk bound II

• Estimation of the risk by the empirical risk. With probability at least $1 - \delta$,

$$L(\widehat{f}) \leq \widehat{L}_n(\widehat{f}) + 2R_n(\ell_{\mathcal{F}}) + \sqrt{\frac{\log(1/\delta)}{2n}}.$$

• The difference from the best possible risk. $f_* = \arg \min_{f \in \mathcal{F}} L(f)$. With probability at least $1 - 2\delta$,

$$L(\widehat{f}) \le L(f_*) + 2R_n(\ell_{\mathcal{F}}) + 2\sqrt{\frac{\log(1/\delta)}{2n}}$$

• Rademacher average $R_n(\mathcal{G})$ expresses the complexity of \mathcal{G} .

$$R_n(\mathcal{G}) = E\left[\sup_{g \in \mathcal{G}} \frac{1}{n} \sum_{i=1}^n \sigma_i g(Z_i)\right],$$

where $\sigma_i \in \{\pm 1\}$ are Rademacher variables (i.i.d. and $\Pr(\sigma_i = 1) = 1/2$.

Hinge loss and 0-1 loss I

Binary classification. $y \in \{\pm 1\}$.

• 0-1 loss:

$$\ell_{01}(y,f) = (1 - y \operatorname{sgn}(f))/2.$$

Risk is often evaluated with 0-1 loss in classification.

$$L(f) = E[\ell_{01}(y, f(X))] = E[Y \neq \operatorname{sgn}(f(X))]$$

• Hinge loss (soft margin loss)

$$\ell_{hinge}(y,f) = \phi(fy), \quad \phi(t) = (1-t)_+$$

used for representing the constraints of soft-margin SVM.*c.f.* SVM

$$\min \widehat{E}_n[\phi(Y_i f(X_i))] + \frac{\lambda}{2} ||f||^2.$$

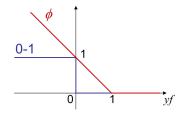
Hinge loss and 0-1 loss II

Truncated hinge loss:

$$\tilde{\phi}(t) = \min(1, \phi(t)).$$

- $\tilde{\phi}$ satisfies $\tilde{\phi}(yf) \in [0,1]$. The results on the uniform bound are applicable.
- Relation:

$$\ell_{01}(y, f(x)) \le \tilde{\phi}(yf(x)) \le \phi(yf(x)).$$



Uniform bound with hinge loss

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$$L(f) = E[\ell_{01}(Y, f(X))] \le E[\tilde{\phi}(Yf(X))].$$

• With probability $\geq 1 - \delta$,

$$\sup_{f\in\mathcal{F}}\left\{E[\tilde{\phi}(Yf(X))] - \widehat{E}_n[\tilde{\phi}(Yf(X))]\right\} \le 2R_n(\ell_{\tilde{\phi},\mathcal{F}}) + \sqrt{\frac{\log(1/\delta)}{2n}},$$

where $\ell_{\tilde{\phi},\mathcal{F}} = \{\tilde{\phi}(yf(x)) \mid f \in \mathcal{F}\}.$

• As a result, With probability $\geq 1 - \delta$,

$$L(f) \leq \underbrace{\widehat{E}_n[\phi(Yf(X))]}_{\text{empirical hinge loss}} + 2R_n(\ell_{\tilde{\phi},\mathcal{F}}) + \sqrt{\frac{\log(1/\delta)}{2n}}$$

for any $f \in \mathcal{F}$.

Uniform bound for SVM

- Recall margin = 1/||w|| (*w*: weight of linear classifier).
- Set the function class

$$\mathcal{F}_r = \{ f \in \mathcal{H}_k \mid \|f\|_{\mathcal{H}_k} \le r \}$$

and consider

$$\min_{f \in \mathcal{H}_k} \widehat{E}_n[\phi(Yf(X))] \qquad \text{subj. to } f \in \mathcal{F}_r.$$

(Slightly different from the original SVM.)

Lemma $R_n(\ell_{\tilde{\phi},\mathcal{F}_r}) \leq R_n(\mathcal{F}_r) \leq r\sqrt{\frac{E[k(X,X)]}{n}}.$

Risk bound for SVM

Risk bound for SVM

Theorem

Let
$$\mathcal{F}_r = \{f \in \mathcal{H}_k \mid ||f||_{\mathcal{H}_k} \leq r\}.$$

With probability $\geq 1 - \delta$,

$$L(f) \le \frac{1}{n} \sum_{i=1}^{n} (1 - Y_i f(X_i))_+ + 2r \sqrt{\frac{E[k(X,X)]}{n}} + \sqrt{\frac{\log(1/\delta)}{2n}}$$
 for any $f \in \mathcal{F}_r$.

- The risk is smaller for a class of larger margin (smaller *r*), assuming that the empirical error is the same.
- The complexity term of the function class does not depend on the dimensionality (≈ number of parameters), but only on the norm.

Proof of Lemma I

$$R_n(\ell_{\tilde{\phi},\mathcal{F}_r}) \leq R_n(\mathcal{F}_r).$$

By definition,

$$R_n(\ell_{\tilde{\phi},\mathcal{F}_r}) = E\bigg[\sup_{f\in\mathcal{F}_r} \frac{1}{n} \sum_{i=1}^n \sigma_i \tilde{\phi}(Y_i f(X_i))\bigg].$$

Since $\tilde{\phi}$ is Lipschitz continuous

$$|\tilde{\phi}(t_1) - \tilde{\phi}(t_2)| \le |t_1 - t_2|,$$

(see Properties of Rademacher averages (5))

$$E\left[\sup_{f\in\mathcal{F}_r}\frac{1}{n}\sum_{i=1}^n\sigma_i\tilde{\phi}(Y_if(X_i))\right] \le E\left[\sup_{f\in\mathcal{F}_r}\frac{1}{n}\sum_{i=1}^n\sigma_iY_if(X_i)\right] = R_n(\mathcal{F}_r).$$

The last equality holds because $\sigma_i Y_i$ are Rademacher variables.

Proof of Lemma II

$$R_n(\mathcal{F}_r) \le r\sqrt{E[k(X,X)]/n}.$$

 $\frac{1}{n}\sum_{i=1}^{n}\sigma_i f(X_i) = \left\langle \frac{1}{n}\sum_{i=1}^{n}\sigma_i k(\cdot, X_i), f \right\rangle \le \|f\| \left\| \frac{1}{n}\sum_{i=1}^{n}\sigma_i k(\cdot, X_i) \right\|.$

Thus,

$$R_n(\mathcal{F}_r) \le rE \left\| \frac{1}{n} \sum_{i=1}^n \sigma_i k(\cdot, X_i) \right\|.$$

$$\begin{split} & \left(E \left\| \frac{1}{n} \sum_{i=1}^{n} \sigma_{i} k(\cdot, X_{i}) \right\| \right)^{2} \\ & \leq E \left\| \frac{1}{n} \sum_{i=1}^{n} \sigma_{i} k(\cdot, X_{i}) \right\|^{2} \qquad [E|\varphi| \leq (E|\varphi|^{2})^{1/2}] \\ & = E \left[\frac{1}{n^{2}} \sum_{i,j=1}^{n} \sigma_{i} \sigma_{j} k(X_{i}, X_{j}) \right] \\ & = \frac{1}{n^{2}} \sum_{i=1}^{n} E \left[k(X_{i}, X_{i}) \right] + \frac{1}{n^{2}} \sum_{i=1}^{n} \sum_{j \neq i} E[\sigma_{i}] E[\sigma_{j}] E[k(X_{i}, X_{j})] \\ & = \frac{1}{n} E[k(X, X)] + 0. \end{split}$$

More on the bound for SVM etc.

- The previous theorem does not reflect the learning of SVM rigorously; the bound is determined as a result of learning, not a priori.
- More rigorous approaches:
 - Bound by fat shattering dimension [BST99].
 - Luckiness framework [Her01].
- Other topics:
 - Generalization of boosting.
 - Relation to the uniform convergence of empirical process (covering number, entropy integral, etc.).

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